Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/662,195	CHANG ET AL.	
Examiner	Art Unit	
lie M. L.	2614	

SEARCHED				
Class	Subclass	Date	Examiner	
375	261	10/15/2006	JL	
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
261	10/15/2006	JL		
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	Subclass	Subclass Date		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
all east databases	10/15/2006	JL.	
inventorship	10/15/2006	JL	
<u>:</u>			
			